## **Power MOSFET**

# -20 V, -2.9 A, Single P-Channel 2.4 x 2.9 x 1.0 mm SOT-23 Package

#### **Features**

- Low R<sub>DS(on)</sub> Solution in 2.4 mm x 2.9 mm Package
- ESD Diode-Protected Gate
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Applications**

- High Side Load Switch
- Battery Switch
- Optimized for Power Management Applications for Portable Products, such as Smart Phones, Media Tablets, PMP, DSC, GPS, and Others

## **MAXIMUM RATINGS** ( $T_J = 25^{\circ}C$ unless otherwise stated)

Parame	Symbol	Value	Unit		
Drain-to-Source Voltage	$V_{DSS}$	-20	V		
Gate-to-Source Voltage	Gate-to-Source Voltage				V
Drain Current (Note 1)					Α
Drain Current (Note 1)	State	T <sub>A</sub> = 85°C		-2.1	
	$t \le 5 \text{ s}$ $T_A = 25^{\circ}\text{C}$			-4.7	
Power Dissipation (Note 1)			P <sub>D</sub>	0.48	W
	t ≤ 5 s			1.25	
Pulsed Drain Current	I <sub>DM</sub>	-8.8	Α		
Operating Junction and Sto	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C		
ESD HBM, JESD22-A114	V <sub>ESD</sub>	2000	V		
Source Current (Body Diod	I <sub>S</sub>	-0.48	Α		
Lead Temperature for Soldering Purposes (1/8 in from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	260	°C/W
Junction-to-Ambient – t ≤ 5 s (Note 1)	$R_{\theta JA}$	100	

- Surface-mounted on FR4 board using 1 in sq. pad size (Cu area = 1.127 in sq. [1 oz] including traces).
- 2. Pulse Test: pulse width ≤ 300 ms, duty cycle ≤ 2%.

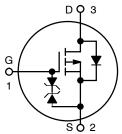


#### ON Semiconductor®

http://onsemi.com

V <sub>(BR)DSS</sub> R <sub>DS(on)</sub> Max		I <sub>D</sub> MAX
-20 V	38 mΩ @ -4.5 V	
	50 mΩ @ -2.5 V	-2.9 A
	73 mΩ @ –1.8 V	

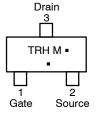
#### P-Channel MOSFET



# MARKING DIAGRAM & PIN ASSIGNMENT



SOT-23 CASE 318 STYLE 21



TRH = Specific Device Code

M = Date Code\*
■ Pb-Free Package

(Note: Microdot may be in either location)

\*Date Code orientation may vary depending upon manufacturing location.

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTR3A30PZT1G	SOT-23 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					-		-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-20			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>	I <sub>D</sub> = -250 μA, ref to 25°C			10.5		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = -20 V				-1	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =	= ±5 V			±10	μΑ
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = -$	250 μΑ	-0.4	-0.65	-1.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				10.5		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = -4.5 V	$I_D = -3 A$		31	38	mΩ
		V <sub>GS</sub> = -2.5 V	I <sub>D</sub> = -2.5 A		36	50	
		V <sub>GS</sub> = -1.8 V	I <sub>D</sub> = -1.5 A		51	73	
Forward Transconductance	9FS	$V_{DS} = -5 \text{ V}, I_D = -3 \text{ A}$			30		S
CHARGES AND CAPACITANCES							
Input Capacitance	C <sub>iss</sub>				1651		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz, } V_{DS} = -15 \text{ V}$			148		]
Reverse Transfer Capacitance	C <sub>rss</sub>				129		
Total Gate Charge	Q <sub>G(TOT)</sub>				17.6		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = -4.5 V, V <sub>DS</sub> = -15 V, I <sub>D</sub> = -3 A			0.7		] !
Gate-to-Source Charge	Q <sub>GS</sub>	$v_{GS} = -4.5 \text{ v}, v_{DS} = -13$	5 V, I <sub>D</sub> = -3 A		2.4		]
Gate-to-Drain Charge	$Q_{GD}$	<u>'</u>			4.9		
SWITCHING CHARACTERISTICS (Note	e 4)						
Turn-On Delay Time	t <sub>d(on)</sub>				100		ns
Rise Time	t <sub>r</sub>	$V_{GS} = -4.5 \text{ V}, V_{DS} = -15 \text{ V},$ $I_{D} = -3 \text{ A}, R_{G} = 6.0 \Omega$			208		
Turn-Off Delay Time	t <sub>d(off)</sub>				1043		
Fall Time	t <sub>f</sub>				552		
DRAIN-SOURCE DIODE CHARACTER	ISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.65	1.0	V
		$I_{S} = -0.4 \text{A}$	T <sub>J</sub> = 125°C		0.47		

Pulse Test: pulse width ≤ 300 ms, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

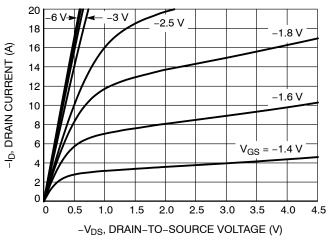


Figure 1. On-Region Characteristics

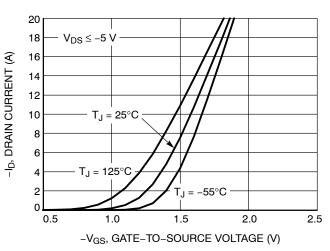


Figure 2. Transfer Characteristics

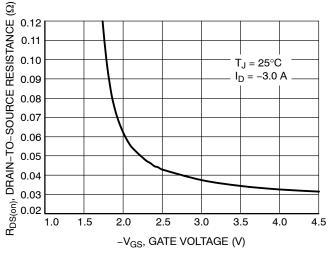


Figure 3. On–Resistance vs. Gate–to–Source Voltage

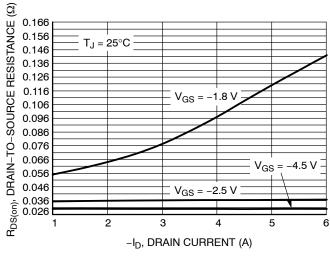


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

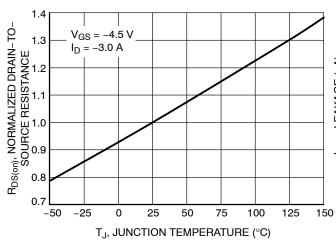


Figure 5. On–Resistance Variation with Temperature

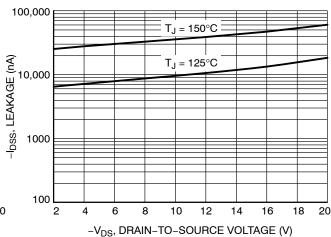


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

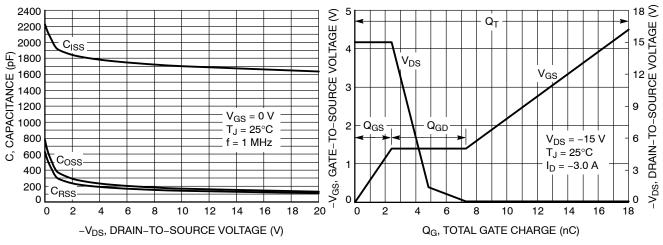


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

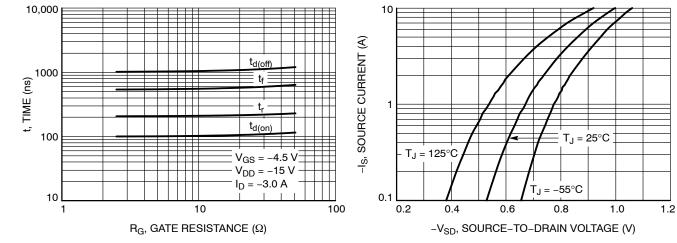


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

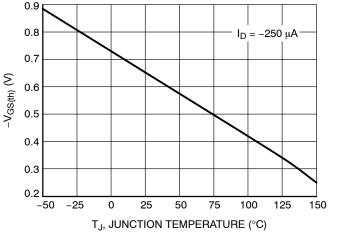


Figure 11. Threshold Voltage

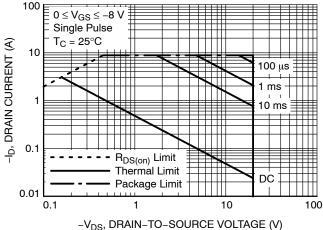


Figure 12. Maximum Rated Forward Biased Safe Operating Area

## **TYPICAL CHARACTERISTICS**

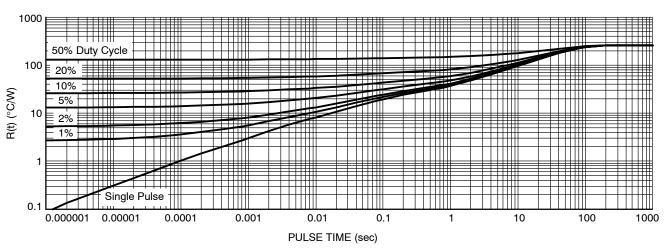
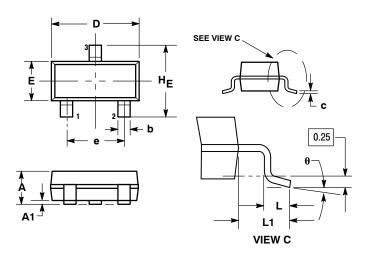


Figure 13. FET Thermal Response

#### PACKAGE DIMENSIONS

#### SOT-23 (TO-236) CASE 318-08 **ISSUE AP**



#### NOTES

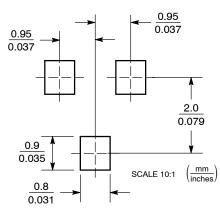
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF BASE MATERIAL
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.89	1.00	1.11	0.035	0.040	0.044
A1	0.01	0.06	0.10	0.001	0.002	0.004
b	0.37	0.44	0.50	0.015	0.018	0.020
С	0.09	0.13	0.18	0.003	0.005	0.007
D	2.80	2.90	3.04	0.110	0.114	0.120
E	1.20	1.30	1.40	0.047	0.051	0.055
е	1.78	1.90	2.04	0.070	0.075	0.081
L	0.10	0.20	0.30	0.004	0.008	0.012
L1	0.35	0.54	0.69	0.014	0.021	0.029
HE	2.10	2.40	2.64	0.083	0.094	0.104
θ	0°		10°	0°		10°

STYLE 21: GATE

2. SOURCE 3. DRAIN

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and un are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking, pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT: Literature Distribution Center for ON Semiconductor

P.O. Box 5163, Denver, Colorado 80217 USA **Phone**: 303–675–2175 or 800–344–3860 Toll Free USA/Canada **Fax**: 303–675–2176 or 800–344–3867 Toll Free USA/Canada

Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative